

Search Notes

Application/Control No.

10/812,040

Examiner

Felix J. Nepveux

Applicant(s)/Patent under
Reexamination

HEER ET AL.

Art Unit

1617

SEARCHED

Class	Subclass	Date	Examiner
424	405	8/7/2005	<i>FJN</i>
514	241	8/7/2005	<i>FJN</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Structure Search	8/1/2005	<i>FJN</i>
Inventor Search	8/7/2005	<i>FJN</i>